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(PTO-1449)		APPLICANT Yasuhiro TAKEDA, et al.					
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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
MK		JP 5-102477 (w/ English Abstract)	04/23/1993	MATSUSHITA ELECTRIC IND. CO., LTD.			
MK		JP 2001-156291 A (w/ English Abstract)	06/08/2001	NEC CORP.			
MK		JP 2000-323710 A (w/ English Abstract)	11/24/2000	CHARTERED SEMICONDUCTOR MFG. LTD.			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
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